

## 高スピン偏極電子源用

## GaAs/GaAsP 歪補償超格子のスピン緩和の観測

## Observation of spin relaxation in GaAs/GaAsP strained-compensated superlattice

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Highly spin-polarized electron sources are intensively developed for applications in high-energy physics and particles physics. Strained superlattice (SL) structures composed of a GaAs-related semiconductors are known to be most effective as the photocathode of a spin-polarized electron beam. A structure with 24-periods of GaAs/GaAsP strain-compensated SL layers demonstrated a maximum spin-polarization of 92% with a high quantum efficiency of 1.6%.<sup>1-3</sup> The increase of the superlattice periods can be effective for the improvement of the quantum efficiency. However, there is a limit of the layer thickness caused by the spin relaxation time. In this study, we have investigated the spin relaxation time of GaAs/GaAsP strain-compensated SL by time-resolved pump and probe measurements.

Figure 1 shows the strained-compensated SL sample structure. After the growth of a 600-nm-thick AlGaAsP buffer layer on GaP substrate, 24-periods GaAs/GaAsP strain-compensated SL layers were grown. Subsequently, the SL structures were coated with a highly doped 5-nm-thick GaAs layer. All layers were doped with Zn.

In the pump and probe measurements, spin-aligned carriers are excited by a circularly polarized optical pulse generated from a Ti-sapphire laser.<sup>4</sup> The photon energy was tuned near the photoluminescence peak wavelength for the transition from the conduction band to the valence band. The PL spectra of GaAs/GaAsP strain-compensated SL is shown in Fig.2. The time resolution of this measurement system is about 200 fs, which was obtained from the time convolution of the optical pulses.

Figure 3 shows the time evolution of spin polarization at room temperature for the excitation power of 110 mW at 781 nm. The measured spin relaxation time of GaAs/GaAsP strain-compensated SL is 104 ps. The conventional 4.5 nm thick-GaAs MQWs show the spin relaxation time of 32 ps at room temperature.<sup>4</sup> The present slow spin relaxation time indicates that GaAs/GaAsP strain-compensated SL is suitable for the highly spin-polarized electron source.

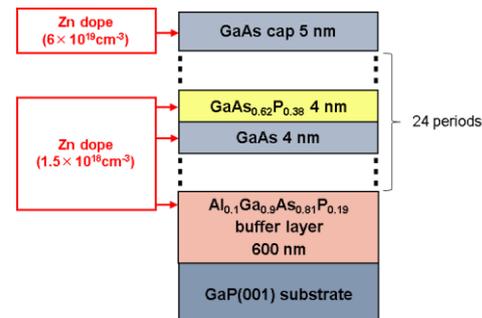


Fig.1 Sample structure of GaAs/GaAsP strain-compensated SL.

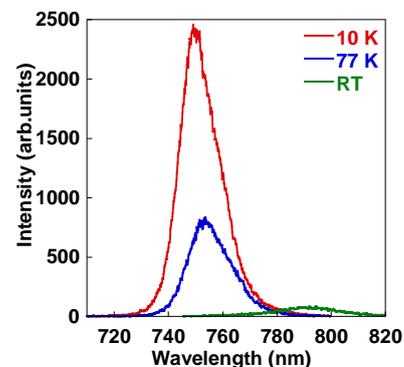


Fig.2 PL spectra of GaAs/GaAsP strain-compensated SL at 10 – RT.

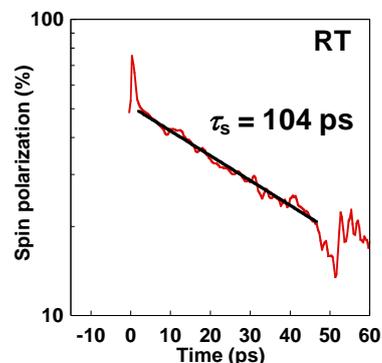


Fig.3 Time evolution of spin polarization at RT for excitation power of 110 mW.

<sup>1</sup> T. Omori et al., Jpn. J. Appl. Phys. **33**, 5676 (1994).<sup>2</sup> T. Saka et al., Surf. Sci. **454**, 1042 (2000).<sup>3</sup> X. G. Jin et al., Appl. Phys. Lett. **105**, 203509 (2014).<sup>4</sup> A. Tackeuchi et al., Appl. Phys. Lett. **56**, 2213 (1990).